

EuFN Workshop Day 1 (June 12th)				
Time	Status	Titel	Presenter	Affiliation
12:30	Get Together, Registration			
13:00	Official Opening		S. Facsko	Head of IBC, HZDR
13:20	Invited	Multigas Plasma FIB (from cell biology to lens manufacturing)	de Marco, A.	Monash University Clayton
13:55	Exhibitor	in situ TEM Lamella LiftOut for Backside Preparation - LO&Flip	Smith, A.	Kleindiek
14:15	Contributed	FIBing Gallium Arsenide (and others): experiments for understanding and limiting artefacts	Audoit, G.	Leti Grenoble
14:35	Exhibitor	Preparation of TEM samples and their observation by means of an adjustable tilt holder	Hrncir, T.	Tescan
14:55	Contributed	Channeling Effects in Gold Nanoclusters under He Ion Irradiation: A Molecular Dynamics Study	Ghaderzadeh, S.	HZDR
15:15	Coffee Break			
16:15	Invited	Microstructure is the "know-it-all" - classification approaches based on 3D-tomography, data mining and deep learning methods	Mücklich, F.	Uni Saarbrücken
16:50	Contributed	AFM-in-SEM LiteScopeTM: Tool for in-situ analysis of FIB modified materials	Novotna, V.	NenoVision
17:10	Exhibitor	In-Situ Correlative AFM/SEM/FIB analysis of FIB-treated samples	Schwalb, C. H.	GETec
17:30	Contributed	Feature Adaptive Sampling for Fast Image Acquisition in FIB and SEM	Pauly, C.	Uni Saarbrücken
17:50	Contributed	Removal of Curtaining Effects by a Variational Model from Mathematical Image Processing	Fitschen, J. H.	Kaiserlautern
EuFN Workshop Day 2 (June 13th)				
9:00	Get Together			
9:15	Invited	Why FIB is essential for analysis in semiconductor industry	Limbecker, P.	Globalfoundries
9:50	Exhibitor	Latest advances of JEOL's JIB-4700F Multi Beam System in focused ion-beam lithography	Harzer, T.	JOEL
10:10	Contributed	Defect production in supported two-dimensional materials under ion irradiation from atomistic simulations: the substrate is crucial	Kretschmer, S.	HZDR
10:30	Coffee Break			
11:00	Exhibitor	Advances in Multiple Ion Species Plasma FIB Technology	Prokhodtseva, A.	Thermo Fisher Scientific
11:20	Exhibitor	An Improved Experimental Setup for the Preparation of Back Side and Planar View TEM samples	Perez Willard, F.	Zeiss
11:40	Exhibitor	Site-specific Atom Probe Tomography Sample Preparation Method by Orthogonal FIB-SEM Column Layout	Onishi, T.	Hitachi
12:00	Lunch			
13:30	Invited	Ion Sources for Focused Ion Beams – Present Status and Prospective Developments	Bischoff, L.	HZDR
14:05	Exhibitor	New Applications in advanced FIB-SEM Nanofabrication with a FIB-centric Lithography System	Stodolka, J.	Raith
14:25	Contributed	SIMPLE – A FIB for Deterministic Single Ion Implantation	Cassidy, N.	University of Surrey
14:45	Exhibitor	3D EBSD and EDS Developments	Larsen, K.	Oxford Instruments
15:05	Contributed	Combined laser and FIB preparation for TEM planar analysis of flash memory cells	Simon-Najasek, M.	FhG IMWS
15:25	Coffee Break			
16:20	Contributed	How FIB induced artefacts influence in situ characterization in the TEM	Berthier, M.	Protechips EMEA
16:40	Contributed	Development of a new integrated instrument for accurate and reproducible physico-chemical characterisation of nanoparticles	De Castro, O.	LIST
17:00	Contributed	TOF-SIMS with highest lateral resolution by pulsing the Ne-GFIS in a HIM	Klingner, N.	HZDR
17:20	Contributed	Combination of the FIB-TOF-SIMS technique with GIS – increasing the ionization probability and sputtering rates of thin films	Priebe, A.	EMPA
Conference Dinner				
EuFN Workshop Day 3 (June 14th)				
9:00	Get Together			
9:15	Invited	Ultrastructural changes accompanying the intracellular mineral formation in alga <i>E. huxleyi</i> : a cryo-FIB/SEM study	Bertinetti, L.	MPIKG Potsdam
9:50	Contributed	Avoiding amorphization during ion beam irradiation and critical dimension reduction of nanostructures	Hlawacek, G.	HZDR
10:10	Contributed	Ultra-fast growth of W-C metal nanostructures by Focused Ion Beam Induced Deposition under cryogenic conditions (cryo-FIBID)	De Teresa, J. M.	University of Zaragoza
10:30	Coffee Break			
11:00	Contributed	Using FIB as a broad ion source for nanofabrication on AlIII-BV(InSb) semiconductors	Jany, B. R.	Jagiellonian University
11:20	Contributed	Creating mesoscale ballistic transport devices from ultra-pure quantum materials	Bachmann, M. D.	MPI-CPFS Dresden
11:40	Contributed	Out-of-plane Transport in ZrSiS, ZrSiSe, and HfSiS Microstructures	Shirer, K. R.	MPI-CPFS Dresden
Concluding Remarks				
Lunch				